

Supporting Information

Designing lanthanide-doped nanocrystals with both up- and down-conversion luminescence for anti-counterfeiting

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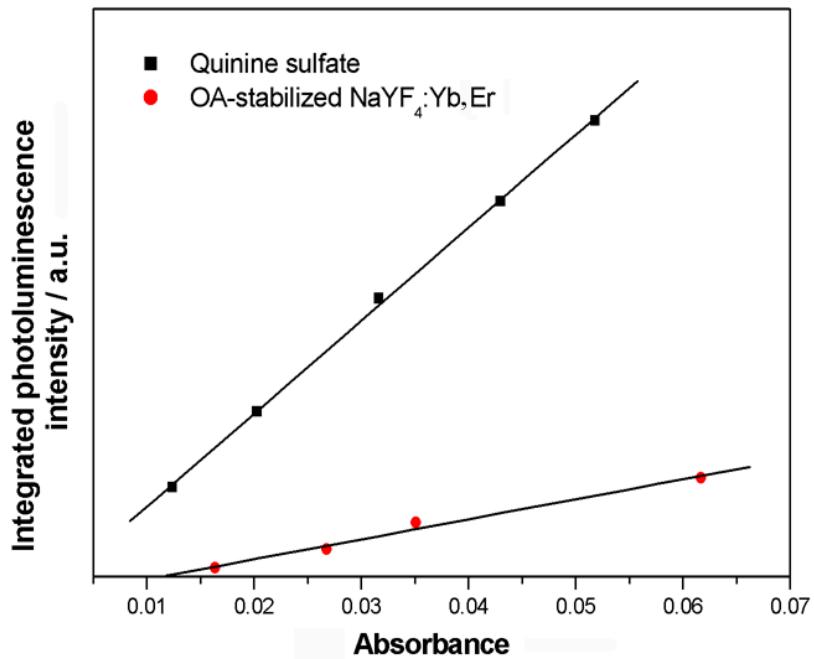


Fig. S1 Integrated fluorescence intensity versus absorbance of oleic acid-stabilized NaYF₄:Yb,Er nanocrystals and quinine sulfate.

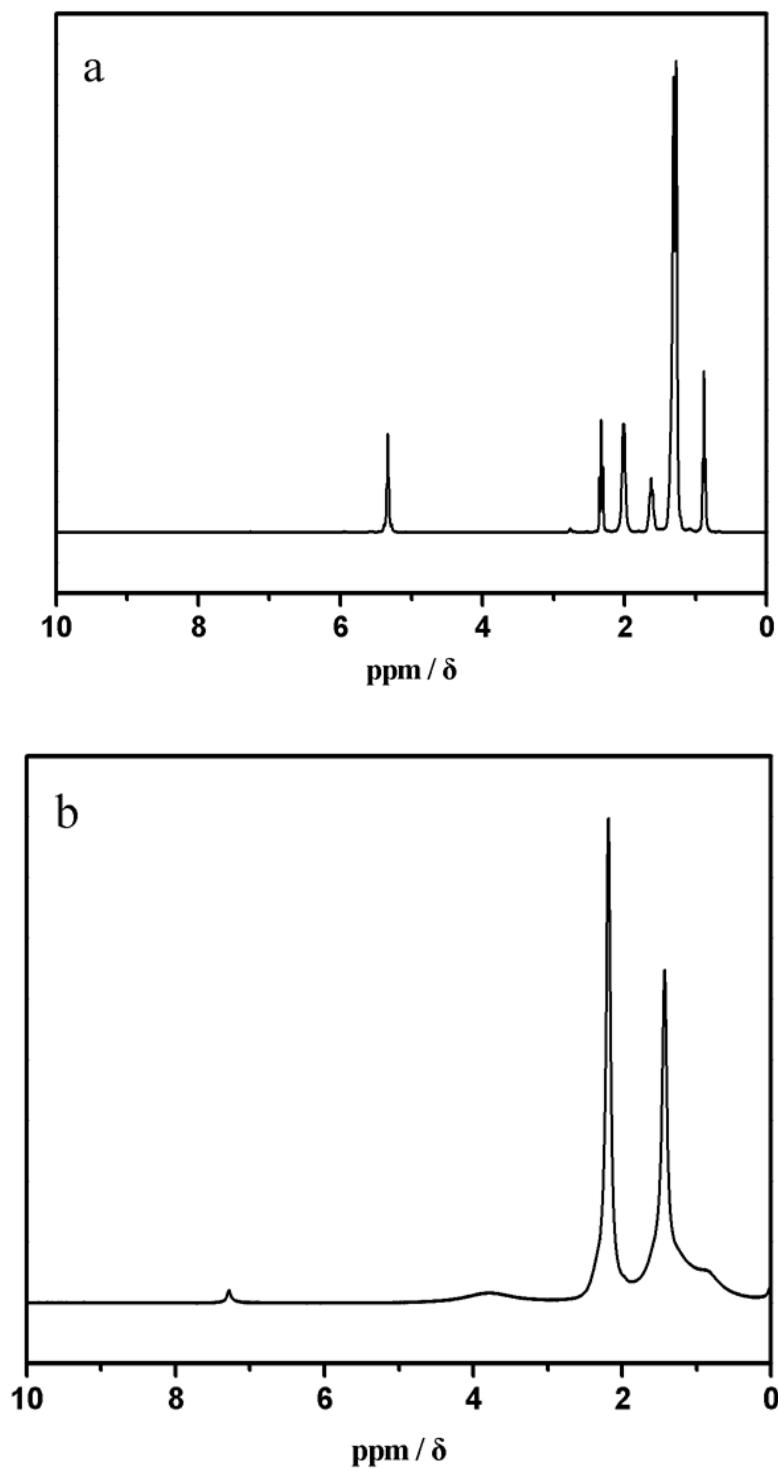


Fig. S2 The ^1H NMR spectra of a) free OA dispersed in CDCl_3 , b) OA-stabilized $\text{NaYF}_4:\text{Yb},\text{Er}$ nanocrystals dispersed in CDCl_3 . Chemical shifts are reported in parts-per-million (δ): 5.2-5.45 (-CH=CH-), 2-2.4 (-CH₂-), 1.2-1.4 (-(CH₂)₆-), 0.8-1.00 (-CH₃).

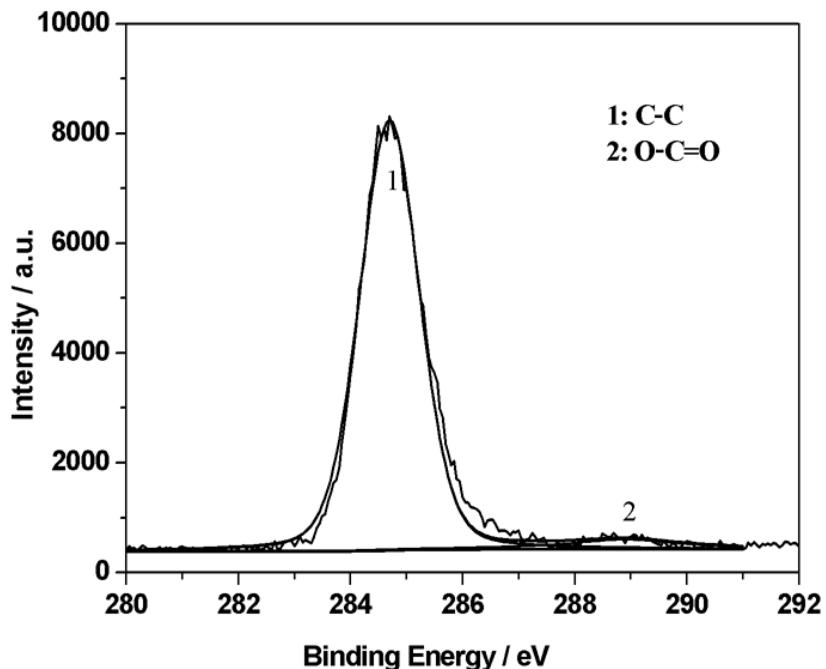


Fig. S3 XPS spectrum of C 1s core-level for the OA-stabilized $\text{NaYF}_4:\text{Yb},\text{Er}$ nanocrystals. C-C (284.6 eV), O-C=O (288.6 eV).¹

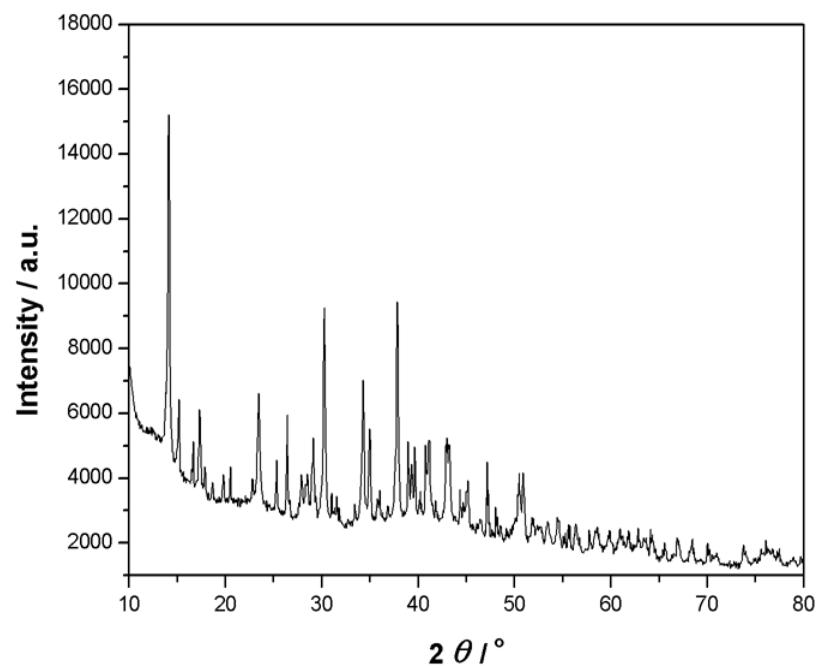


Fig. S4 XRD pattern of the product obtained after evaporating YCl_3 aqueous solution.

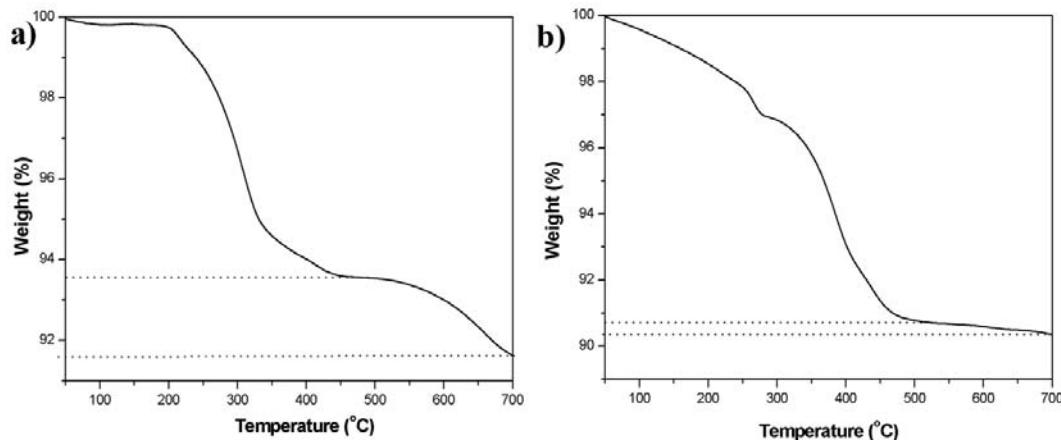


Fig. S5 TGA curves of a) oleic acid-stabilized $\text{NaYF}_4:\text{Yb},\text{Er}$ nanocrystals prepared in our strategy and b) oleic acid-stabilized $\text{NaYF}_4:\text{Yb},\text{Er}$ nanocrystals obtained by the thermal-decomposition trifluoroacetates method.

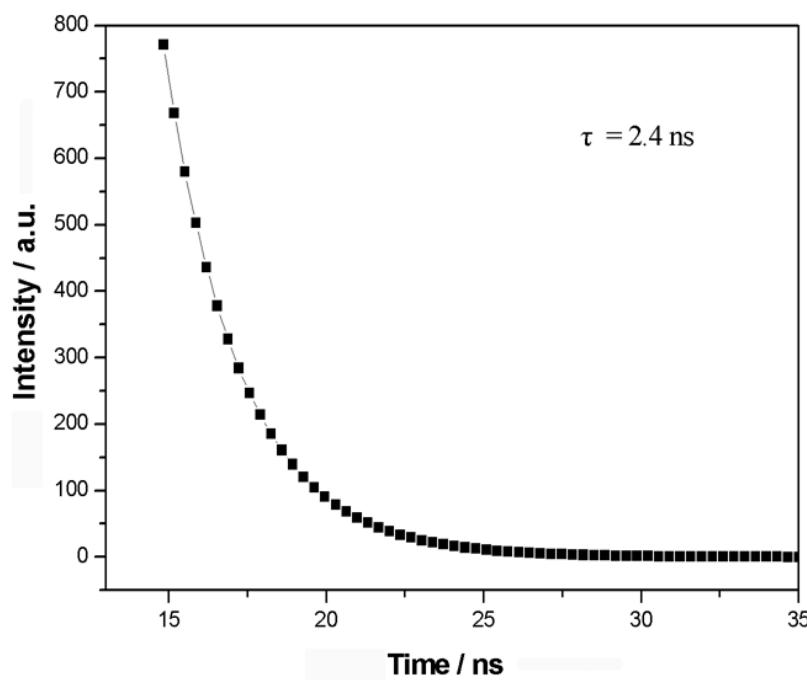


Fig. S6 Fluorescence decay curve of oleic acid-stabilized $\text{NaYF}_4:\text{Yb},\text{Er}$ nanocrystals in cyclohexane.

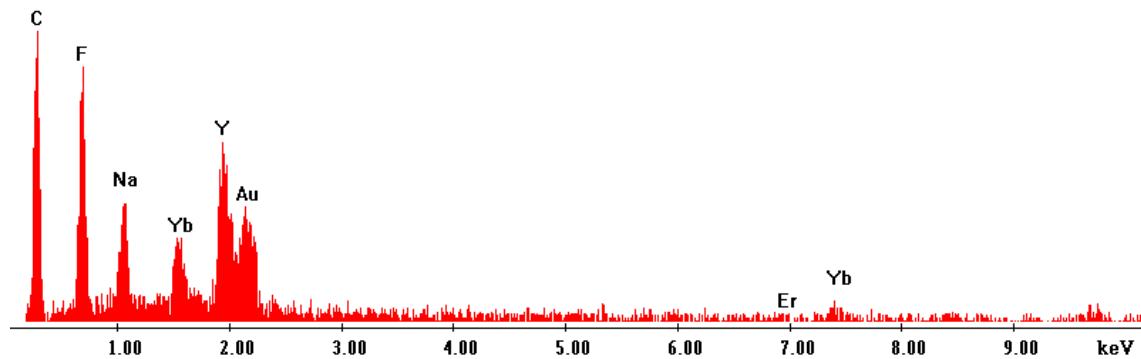


Fig. S7 EDX pattern of the fingerprint impressed on the transparent film.

samples	NaYF ₄ :Yb,Tm	NaYF ₄ :Yb,Er	NaYbF ₄ :Er
stoichiometric molar ratio of Y/Yb/Er/Tm	0.75:0.25:0.003	0.80:0.18:0.02	0.98:0.02
actual molar ratio of Y/Yb/Er/Tm	0.74:0.247:0.003	0.762:0.186:0.02	0.981:0.02

Table S1. Stoichiometric and actual molar ratios of Y/Yb/Er, Y/Yb/Tm and Yb/Er in lanthanide-doped fluoride nanocrystals.

1 L. Y. Cao, Y. L. Liu, B. H. Zhang, L. H. Lu, *Appl. Mater. Interf.* 2010, **2**, 2339.